Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	45	(reflectivity same throughput) and (thickness same micron$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:57
L2	31	(reflectivity same throughput) and (thickness with micron$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:53
L3	6	(reflectivity with throughput) and (thickness with micron$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:05
L4	9	l1 and x-ray$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:39
L5	738	symyx	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:55
L6	0	l1 and l5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:55
L7	8	(reflectivity same throughput) and (thickness same micrometer$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:57
L8	20077	combinatorial and librar$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:57
L9	546	(reflectivity and throughput) and (thickness same micron$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:57

L10	34	I8 and I9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:05
L11	0	I5 and I10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 17:57
L12	3731	reflectivity and (thickness with micron$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:05
L13	41	I8 and I12	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:23
L14	119	(sample adj thickness) with microns	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:30
L15	45	I14 and reflect$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:32
L16	522	optical with reflection with profil$9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:32
L17	172	I16 and micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:32
L18	17	I16 and x-ray$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:38
L19	4486	screen$5 and librar$5 and reflect$8 and thickness$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:39

L20	1818	I19 and micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:41
L21	1588	I19 and x-ray$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:39
L22	859	I20 and x-ray$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:39
L23	6	screen$5 same librar$5 same reflect$8 same thickness$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:40
L24	0	I6 and micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:41
L25	4	I23 and micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:46
L26	626	x-ray with reflectivity	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:46
L27	1587	sample with thickness with micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:48
L28	1	I26 and I27	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:47
L29	716	sample with thickness with micrometer$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:47

L30	0	I26 and I29	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:48
L31	107240	thickness with micron$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:48
L32	45	I26 and I31	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/23 18:48